



**THE DATASHEET OF  
ZXMD63C03XTA**



## Product Summary

Device	$V_{(BR)DSS}$	$R_{DS(ON)}$	$I_D$
N-Channel	30V	0.135Ω	2.3A
P-Channel	-30V	0.185Ω	-2.0A

## Description

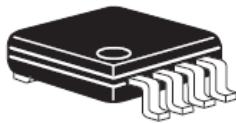
This new generation of high density MOSFETs from Diodes Incorporated utilizes a unique structure that combines the benefits of low on-resistance with fast switching speed. This makes them ideal for high efficiency, low voltage, power management applications.

## Features

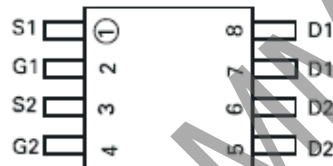
- Low On-resistance
- Fast Switching Speed
- Low Threshold
- Low Gate Drive
- Low Profile SOIC Package

## Applications

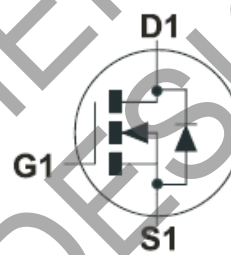
- DC - DC Converters
- Power Management Functions
- Disconnect Switches
- Motor Control



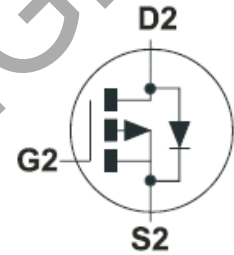
MSOP8



Pin-Out  
Top View



N-channel



P-channel

## Ordering Information

Part Number	Device Marking	Reel Size (inches)	Tape Width (mm)	Quantity Per Reel
ZXMD63C03XTA	ZXM63C03	7	12mm Embossed	1000 Units
ZXMD63C03XTC	ZXM63C03	13	12mm Embossed	4000 Units

## Maximum Ratings

PARAMETER	SYMBOL	N-CHANNEL	P-CHANNEL	UNIT
Drain-Source Voltage	$V_{DSS}$	30	-30	V
Gate- Source Voltage	$V_{GS}$	$\pm 20$		V
Continuous Drain Current ( $V_{GS}=4.5V$ ; $T_A=25^\circ C$ )(b)(d) ( $V_{GS}=4.5V$ ; $T_A=70^\circ C$ )(b)(d)	$I_D$	2.3	-2.0	A
		1.8	-1.6	A
Pulsed Drain Current (c)(d)	$I_{DM}$	14	-9.6	A
Continuous Source Current (Body Diode)(b)(d)	$I_S$	1.5	-1.4	A
Pulsed Source Current (Body Diode)(c)(d)	$I_{SM}$	14	-9.6	A
Power Dissipation at $T_A=25^\circ C$ (a)(d) Linear Derating Factor	$P_D$	0.87 6.9		W mW/ $^\circ C$
Power Dissipation at $T_A=25^\circ C$ (a)(e) Linear Derating Factor	$P_D$	1.04 8.3		W mW/ $^\circ C$
Power Dissipation at $T_A=25^\circ C$ (b)(d) Linear Derating Factor	$P_D$	1.25 10		W mW/ $^\circ C$
Operating and Storage Temperature Range	$T_J:T_{stg}$	-55 to +150		$^\circ C$

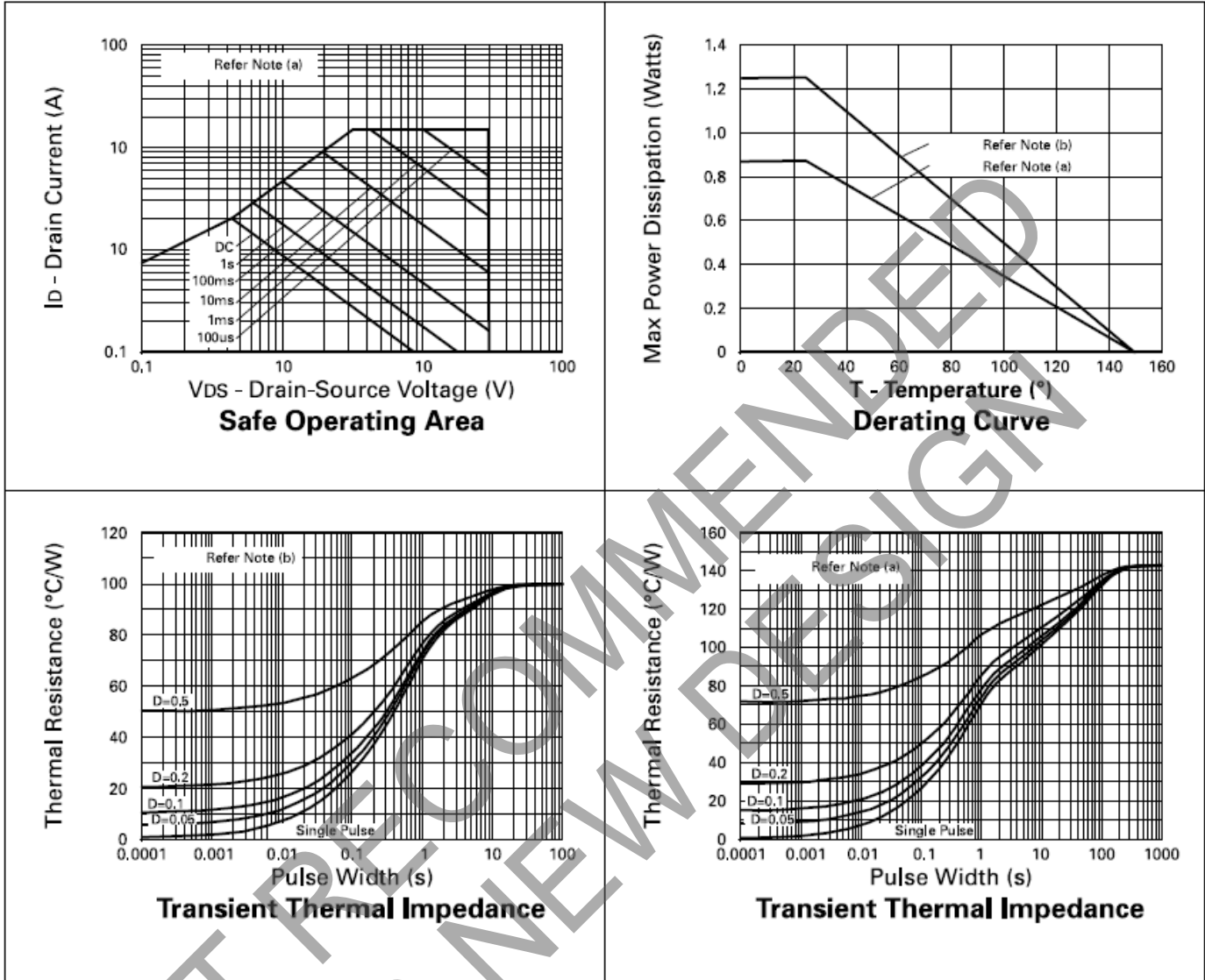
## Thermal Characteristics

PARAMETER	SYMBOL	VALUE	UNIT
Junction to Ambient (a)(d)	$R_{\theta JA}$	143	$^\circ C/W$
Junction to Ambient (b)(d)	$R_{\theta JA}$	100	$^\circ C/W$
Junction to Ambient (a)(e)	$R_{\theta JA}$	120	$^\circ C/W$

**NOTES:**

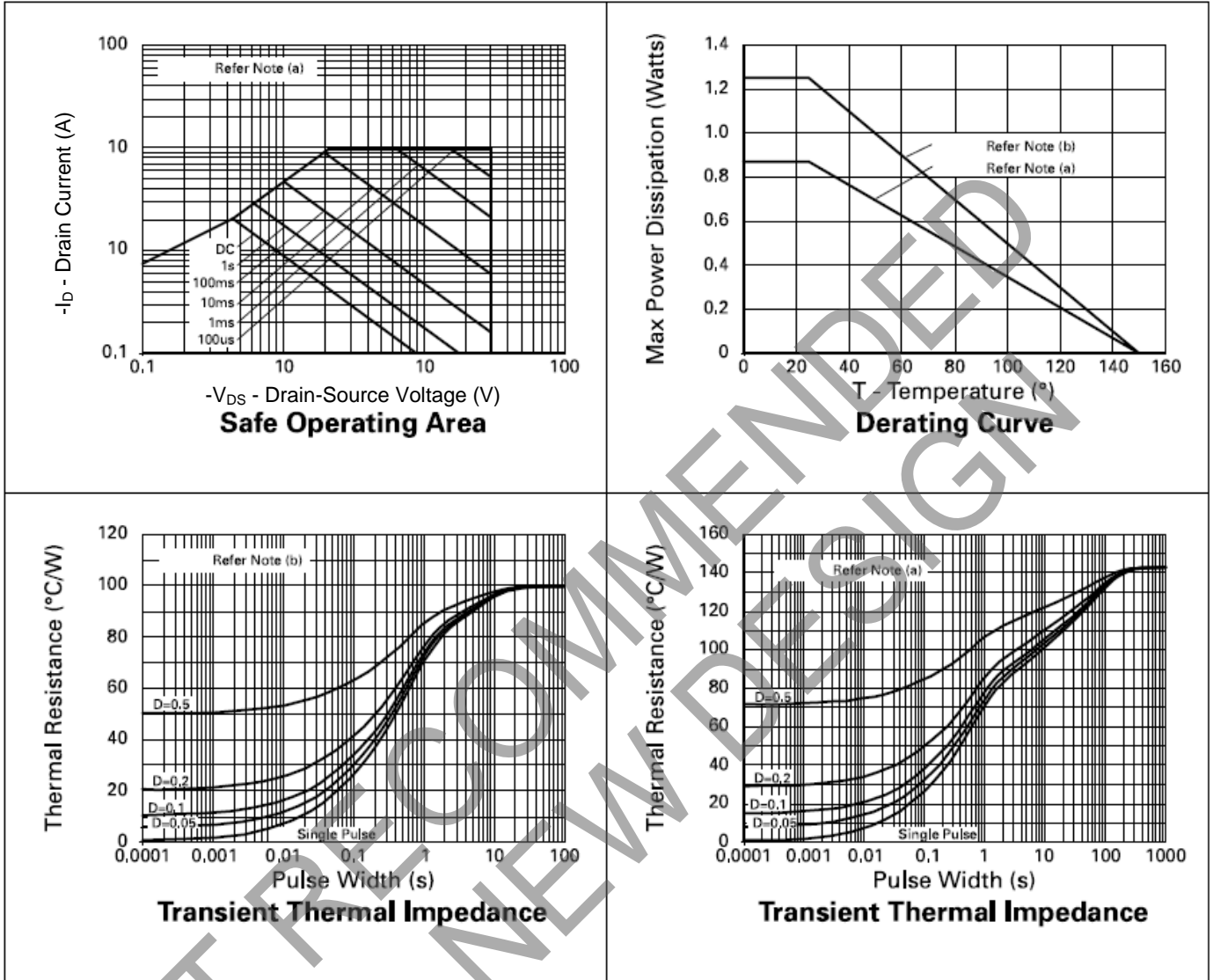
- (a) For a device surface mounted on 25mm x 25mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions
- (b) For a device surface mounted on FR4 PCB measured at  $t \leq 10$  secs.
- (c) Repetitive rating - pulse width limited by maximum junction temperature. Refer to Transient Thermal Impedance graph.
- (d) For device with one active die.
- (e) For device with two active die running at equal power.

**N-Channel Characteristics**



NOT RECOMMENDED FOR NEW DESIGN

**P-Channel Characteristics**



NOT FOR NEW DESIGN

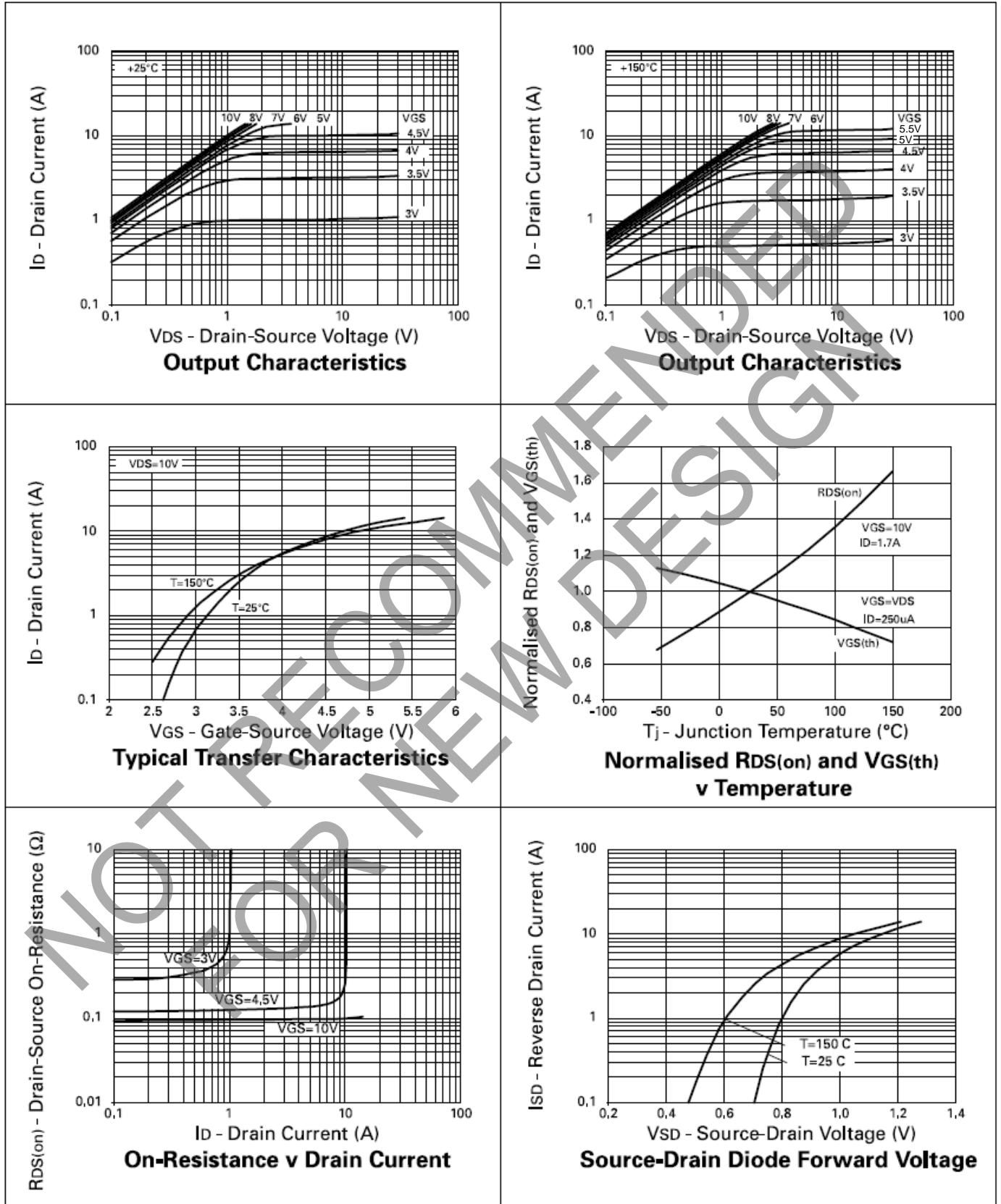
**Electrical Characteristics – N-Channel** (@T<sub>A</sub> = +25°C, unless otherwise specified.)

PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT	CONDITIONS
<b>STATIC</b>						
Drain-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	30			V	I <sub>D</sub> =250μA, V <sub>GS</sub> =0V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>			1	μA	V <sub>DS</sub> =30V, V <sub>GS</sub> =0V
Gate-Body Leakage	I <sub>GSS</sub>			100	nA	V <sub>GS</sub> =± 20V, V <sub>DS</sub> =0V
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	1.0			V	I <sub>D</sub> =250μA, V <sub>DS</sub> =V <sub>GS</sub>
Static Drain-Source On-State Resistance (1)	R <sub>DS(on)</sub>			0.135 0.200	Ω	V <sub>GS</sub> =10V, I <sub>D</sub> =1.7A V <sub>GS</sub> =4.5V, I <sub>D</sub> =0.85A
Forward Transconductance (3)	g <sub>fs</sub>	1.9			S	V <sub>DS</sub> =10V, I <sub>D</sub> =0.85A
<b>DYNAMIC (3)</b>						
Input Capacitance	C <sub>iss</sub>		290		pF	V <sub>DS</sub> =25V, V <sub>GS</sub> =0V, f=1MHz
Output Capacitance	C <sub>oss</sub>		70		pF	
Reverse Transfer Capacitance	C <sub>rss</sub>		20		pF	
<b>SWITCHING(2) (3)</b>						
Turn-On Delay Time	t <sub>d(on)</sub>		2.5		ns	V <sub>DD</sub> = 15V, I <sub>D</sub> =1.7A R <sub>G</sub> =6.1Ω, R <sub>D</sub> =8.7Ω (Refer to test circuit)
Rise Time	t <sub>r</sub>		4.1		ns	
Turn-Off Delay Time	t <sub>d(off)</sub>		9.6		ns	
Fall Time	t <sub>f</sub>		4.4		ns	
Total Gate Charge	Q <sub>g</sub>			8	nC	V <sub>DS</sub> =24V, V <sub>GS</sub> =10V, I <sub>D</sub> =1.7A (Refer to test circuit)
Gate-Source Charge	Q <sub>gs</sub>			1.2	nC	
Gate Drain Charge	Q <sub>gd</sub>			2	nC	
<b>SOURCE-DRAIN DIODE</b>						
Diode Forward Voltage (1)	V <sub>SD</sub>			0.95	V	T <sub>J</sub> =25°C, I <sub>S</sub> =1.7A, V <sub>GS</sub> =0V
Reverse Recovery Time (3)	t <sub>rr</sub>		16.9		ns	T <sub>J</sub> =25°C, I <sub>F</sub> =1.7A, di/dt= 100A/μs
Reverse Recovery Charge(3)	Q <sub>rr</sub>		9.5		nC	

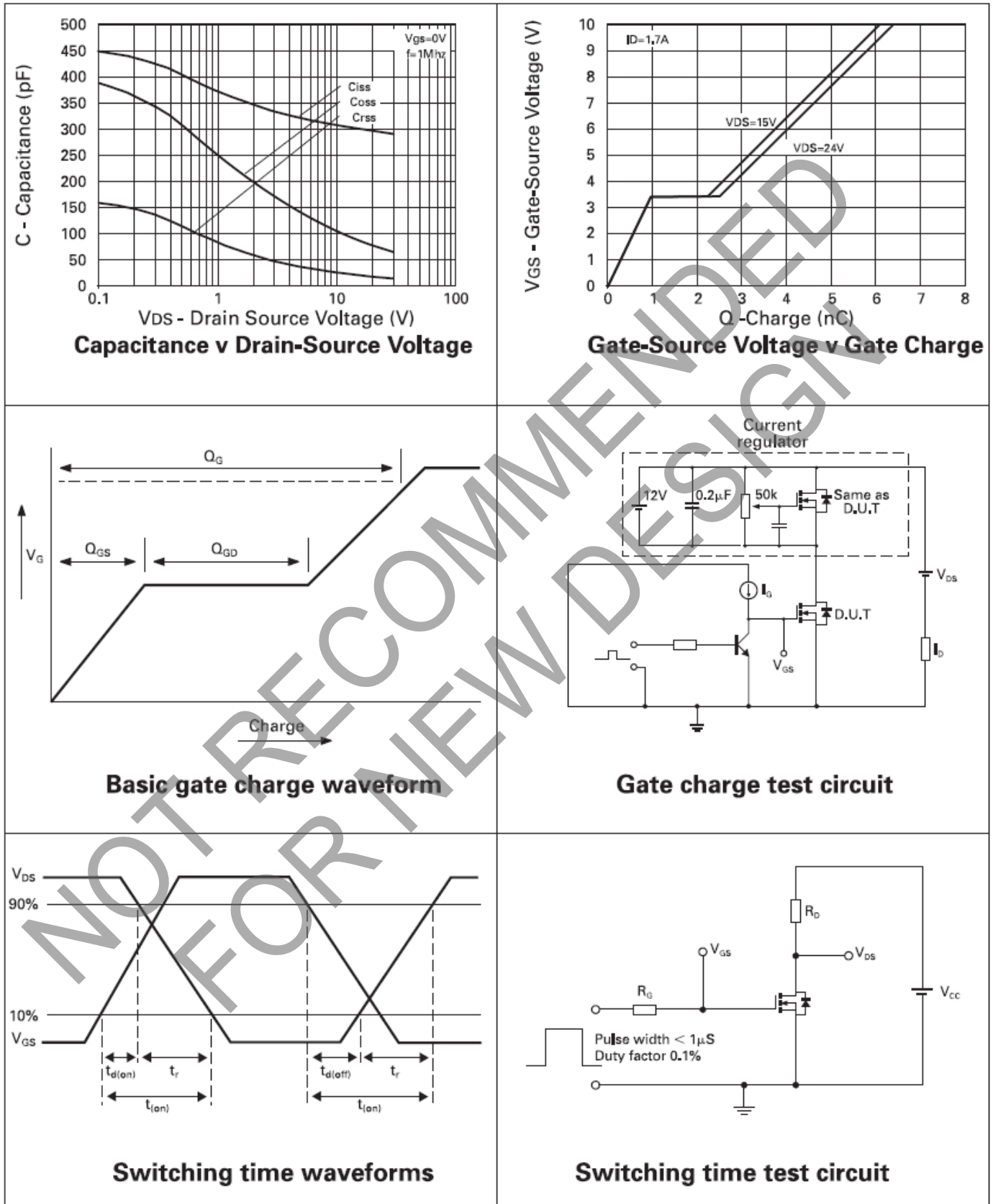
**NOTES:**

- (1) Measured under pulsed conditions. Width=300μs. Duty cycle ≤2%.
- (2) Switching characteristics are independent of operating junction temperature.
- (3) For design aid only, not subject to production testing.

**N-Channel Typical Characteristics**



**N-Channel Characteristics**



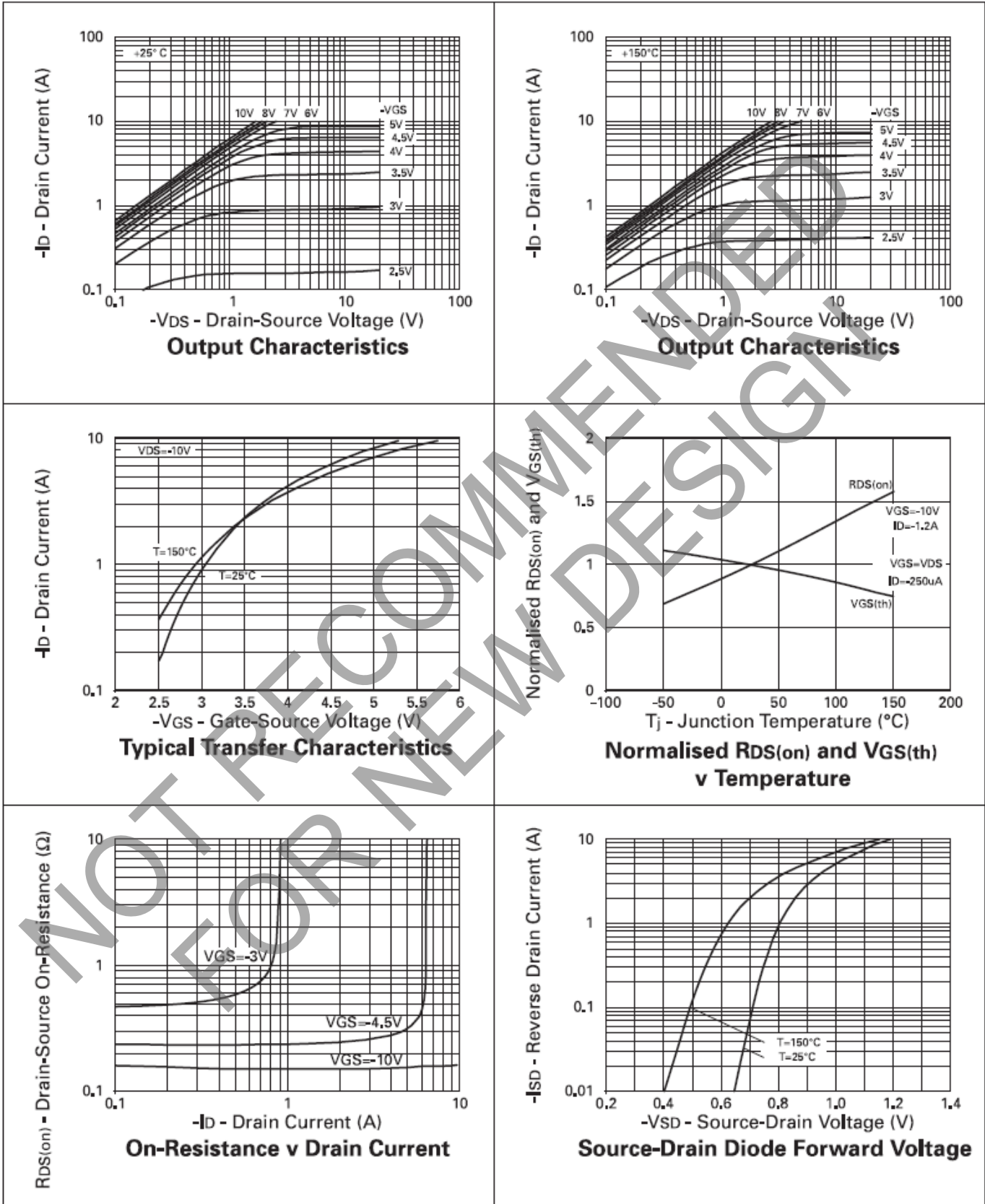
**Electrical Characteristics – P-Channel** (@T<sub>A</sub> = +25°C, unless otherwise specified.)

PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT	CONDITIONS
<b>STATIC</b>						
Drain-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	-30			V	I <sub>D</sub> =-250μA, V <sub>GS</sub> =0V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>			-1	μA	V <sub>DS</sub> =-30V, V <sub>GS</sub> =0V
Gate-Body Leakage	I <sub>GSS</sub>			±100	nA	V <sub>GS</sub> =±20V, V <sub>DS</sub> =0V
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	-1.0			V	I <sub>D</sub> =-250μA, V <sub>DS</sub> =V <sub>GS</sub>
Static Drain-Source On-State Resistance (1)	R <sub>DS(on)</sub>			0.185 0.27	Ω Ω	V <sub>GS</sub> =-10V, I <sub>D</sub> =1.2A V <sub>GS</sub> =-4.5V, I <sub>D</sub> =0.6A
Forward Transconductance (3)	g <sub>fs</sub>	0.92			S	V <sub>DS</sub> =-10V, I <sub>D</sub> =-0.6A
<b>DYNAMIC (3)</b>						
Input Capacitance	C <sub>iss</sub>		270		pF	V <sub>DS</sub> =-25V, V <sub>GS</sub> =0V, f=1MHz
Output Capacitance	C <sub>oss</sub>		80		pF	
Reverse Transfer Capacitance	C <sub>rss</sub>		30		pF	
<b>SWITCHING(2) (3)</b>						
Turn-On Delay Time	t <sub>d(on)</sub>		2.6		ns	V <sub>DD</sub> =-15V, I <sub>D</sub> =-1.2A R <sub>G</sub> =6.2Ω, R <sub>D</sub> =6.2Ω (Refer to test circuit)
Rise Time	t <sub>r</sub>		4.8		ns	
Turn-Off Delay Time	t <sub>d(off)</sub>		13.1		ns	
Fall Time	t <sub>f</sub>		9.3		ns	
Total Gate Charge	Q <sub>g</sub>			7	nC	V <sub>DS</sub> =-24V, V <sub>GS</sub> =-10V, I <sub>D</sub> =-1.2A (Refer to test circuit)
Gate-Source Charge	Q <sub>gs</sub>			1.2	nC	
Gate Drain Charge	Q <sub>gd</sub>			2	nC	
<b>SOURCE-DRAIN DIODE</b>						
Diode Forward Voltage (1)	V <sub>SD</sub>			-0.95	V	T <sub>J</sub> =25°C, I <sub>S</sub> =-1.2A, V <sub>GS</sub> =0V
Reverse Recovery Time (3)	t <sub>rr</sub>		21.4		ns	T <sub>J</sub> =25°C, I <sub>F</sub> =-1.2A, di/dt= 100A/μs
Reverse Recovery Charge(3)	Q <sub>rr</sub>		15.7		nC	

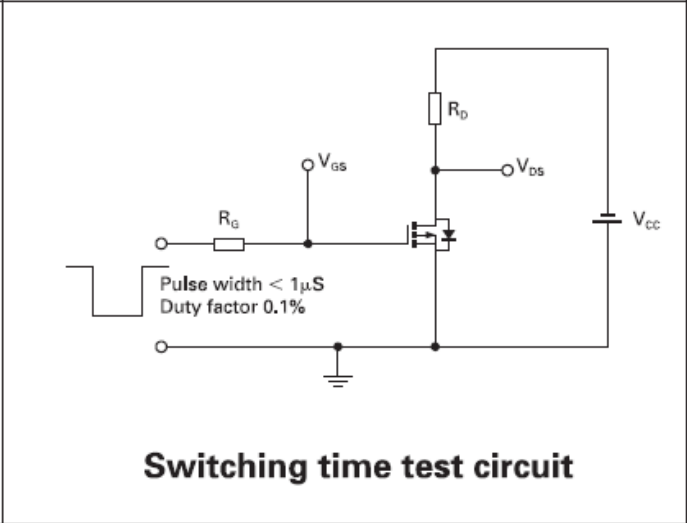
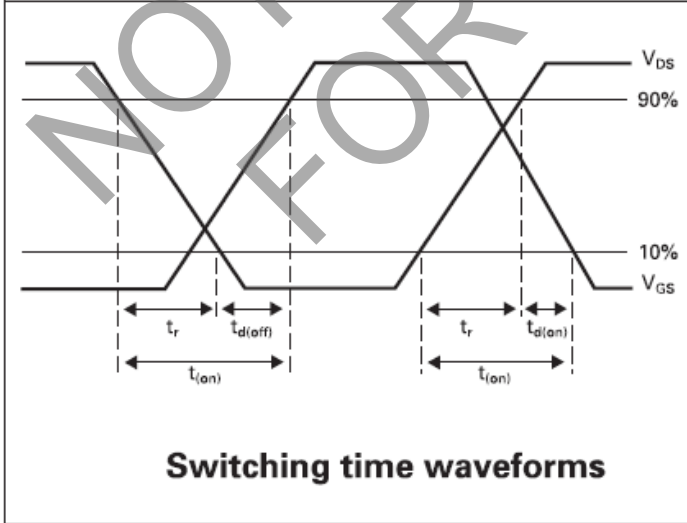
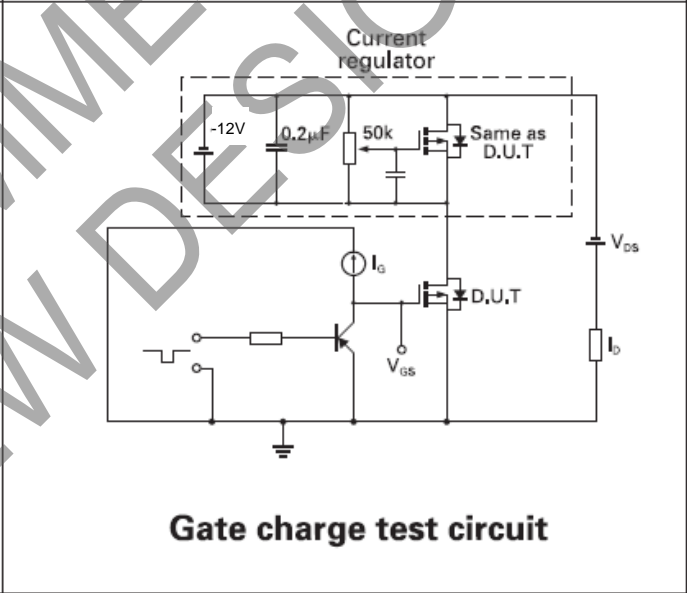
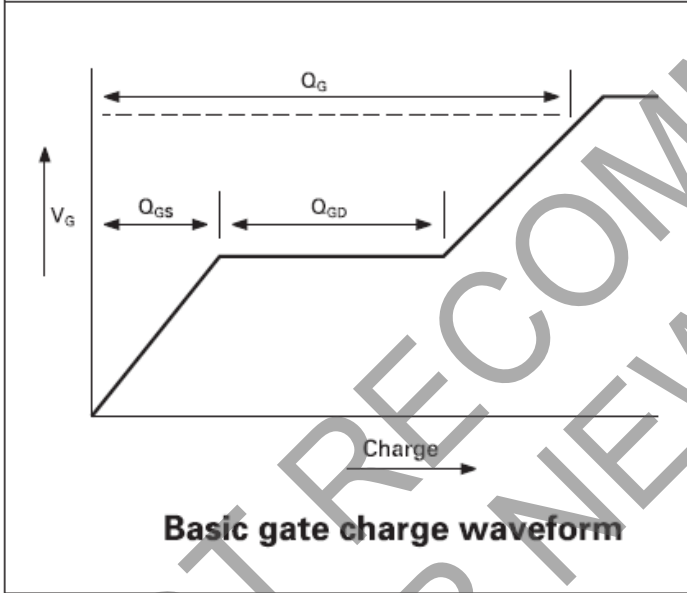
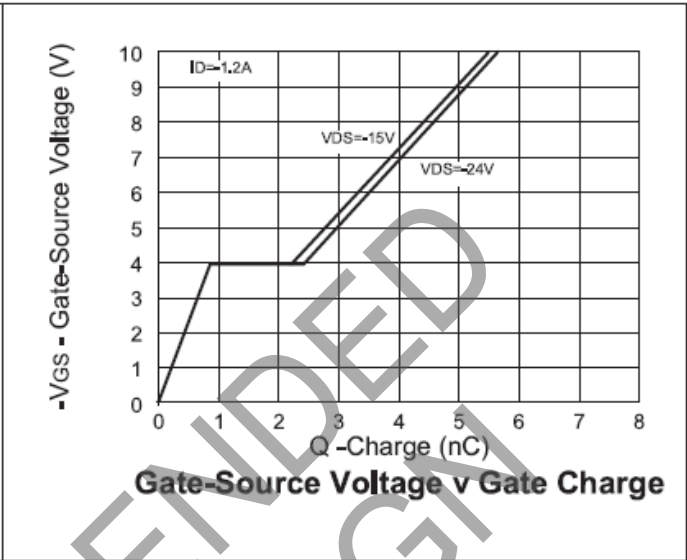
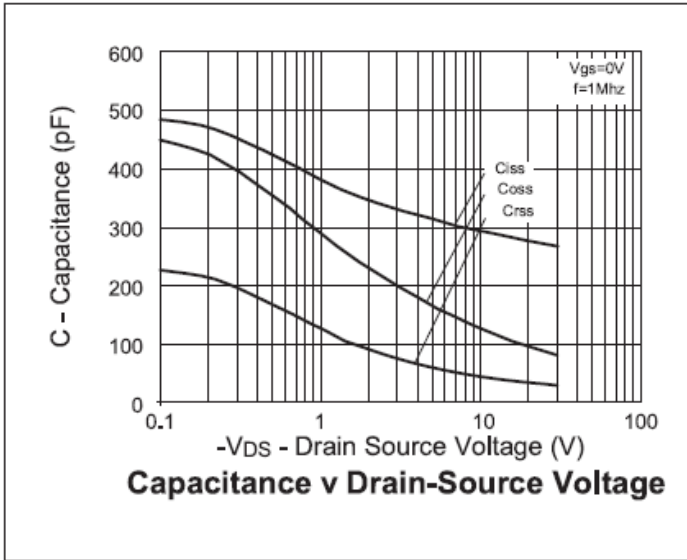
**NOTES:**

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**P-Channel Characteristics**



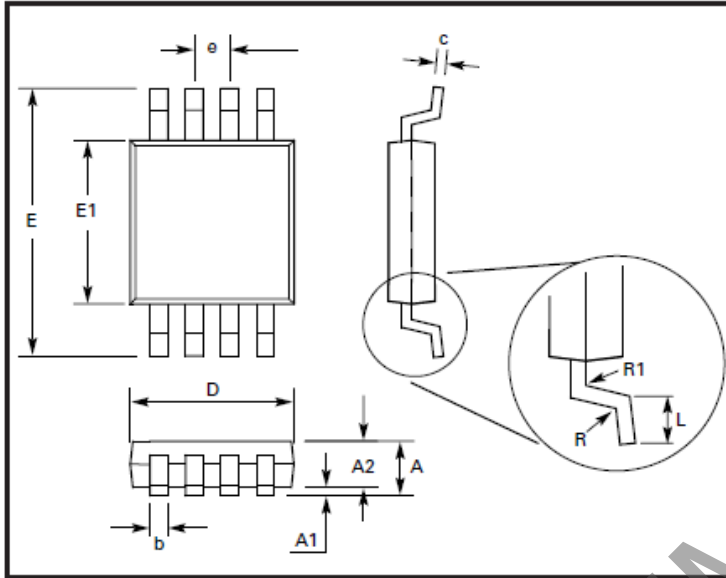
**P-Channel Typical Characteristics**



**Package Outline Dimensions**

Please see <http://www.diodes.com/package-outlines.html> for the latest version.

**MSOP8**

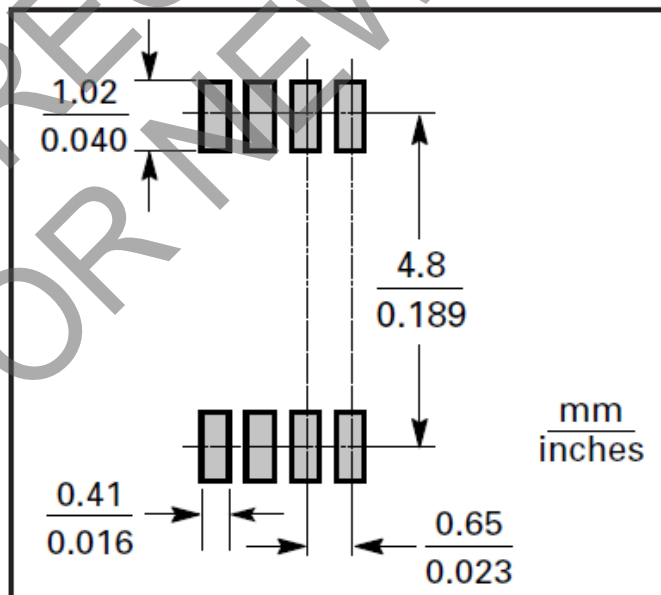


DIM	Millimeters		Inches	
	Min.	Max.	Min.	Max.
A	-	1.10	-	0.0433
A1	0.05	0.15	0.002	0.006
A2	0.75	0.95	0.0295	0.0374
b	0.25	0.40	0.010	0.0157
c	0.13	0.23	0.005	0.009
D	2.90	3.10	0.114	0.122
E	4.90 BSC		0.193 BSC	
E1	2.90	3.10	0.114	0.122
e	0.65 BSC		0.025 BSC	
L	0.40	0.70	0.0157	0.0192
R	0.07	-	0.0027	-
R1	0.07	-	0.0027	-

**Suggested Pad Layout**

Please see <http://www.diodes.com/package-outlines.html> for the latest version.

**MSOP8**



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